

Aug 03, 2015

To: FCC

From: CCIC-SET

RE: Applicant: Haier Telecom (Qingdao) Co.,Ltd.,

FCC ID: SG720150715G30, Request for supercede of Part15 B report.

The margin of conducted emission of the original Part15 B report are not provide, therefore, we are asking to kindly replace the Part15 B report with revised copies. No influence on the test results.

You can find the changes on page 12, 13 of the revised Part15 B report,

Original part 15B report table;

original part 13B report table,									
Conducted Disturbance at Mains Terminals									
L Test Data									
QP AV									
Frequen cy (MHz)	Limits (dBµV)	Measurem ent Value (dBμV)	Margin (dB)	Frequen cy (MHz)	Limits (dBµV)	Measurem ent Value (dBμV)	Margin (dB)		
0.2040	63.40	56.16		0.2040	53.40	43.14			
0.3390	59.20	49.26		0.3390	49.20	41.15			
0.4065	57.70	46.37		0.4065	47.70	38.38			

Conducted Disturbance at Mains Terminals									
	N Test Data								
	QP				AV				
Frequen cy (MHz)	Limits (dBµV)	Measureme nt Value (dBμV)	Margin (dB)	Frequency (MHz)	Limits (dBµV)	Measureme nt Value (dBµV)	Margin (dB)		
0.2040	63.40	53.39		0.1500	56.00	41.19			
0.3280	59.50	54.13		0.3280	49.50	36.46			
0.4150	57.50	44.36		0.4150	47.50	34.25			



New 15B report table:

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Conducted Disturbance at Mains Terminals							
L Test Data							
QP				AV			
Frequen cy (MHz)	Limits (dBµV)	Measurem ent Value (dBμV)	Margin (dB)	Frequen cy (MHz)	Limits (dBµV)	Measurem ent Value (dBμV)	Margin (dB)
0.2040	63.40	56.16	7.24	0.2040	53.40	43.14	10.26
0.3390	59.20	49.26	9.94	0.3390	49.20	41.15	8.05
0.4065	57.70	46.37	11.33	0.4065	47.70	38.38	9.32

Conducted Disturbance at Mains Terminals								
N Test Data								
QP				AV				
Frequen cy (MHz)	Limits (dBµV)	Measureme nt Value (dBμV)	Margin (dB)	Frequency (MHz)	Limits (dBµV)	Measureme nt Value (dBμV)	Margin (dB)	
0.2040	63.40	53.39	10.01	0.1500	56.00	41.19	14.81	
0.3280	59.50	54.13	5.37	0.3280	49.50	36.46	13.04	
0.4150	57.50	44.36	13.14	0.4150	47.50	34.25	13.25	

Thank you,

Shuangwen Zhang

CCIC-SET

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